

L Number	Hits	Search Text	DB	Time stamp
3	5	("silicon nitride" or SiN or dielectric ) same (aluminum or Al or conductive ) same (opening or via or hole ) same ("xenon difluoride" or "XeF.sub.2")	USPAT; EPO; JPO; IBM_TDB	2002/07/15 14:23
4	90	("silicon nitride" or SiN or dielectric ) and (aluminum or Al or conductive ) and (opening or via or hole ) and ("xenon difluoride" or "XeF.sub.2")	USPAT; EPO; JPO; IBM_TDB	2002/07/15 14:14
6	43271	("silicon nitride" or SiN or dielectric ) and (aluminum or Al or conductive ) and (opening or via or hole ) and etch\$3	USPAT; EPO; JPO; IBM_TDB	2002/07/15 14:13
7	11302	((("silicon nitride" or SiN or dielectric ) and (aluminum or Al or conductive ) and (opening or via or hole ) and etch\$3) and (capacitor or inductor)	USPAT; EPO; JPO; IBM_TDB	2002/07/15 14:13
8	11302	((("silicon nitride" or SiN or dielectric ) and (aluminum or Al or conductive ) and (opening or via or hole ) and etch\$3) and (capacitor or inductor)	USPAT; EPO; JPO; IBM_TDB	2002/07/15 14:14
9	29	((("silicon nitride" or SiN or dielectric ) and (aluminum or Al or conductive ) and (opening or via or hole ) and etch\$3) and (capacitor or inductor)) and ("xenon difluoride" or "XeF.sub.2")	USPAT; EPO; JPO; IBM_TDB	2002/07/15 15:38
10	1882	("silicon nitride" or SiN or dielectric ) same (aluminum or Al or conductive ) same (openings or via or hole ) same (inductor or capacitor)	USPAT; EPO; JPO; IBM_TDB	2002/07/15 14:27
12	612	((("silicon nitride" or SiN or dielectric ) same (aluminum or Al or conductive ) same (openings or via or hole ) same (inductor or capacitor)) same etch\$4	USPAT; EPO; JPO; IBM_TDB	2002/07/15 14:28
13	542	((("silicon nitride" or SiN or dielectric ) same (aluminum or Al or conductive ) same (openings or via or hole ) same (inductor or capacitor)) same etch\$4) and semiconductor	USPAT; EPO; JPO; IBM_TDB	2002/07/15 14:29
19	85	((("silicon nitride" or SiN or dielectric ) and (aluminum or Al or conductive ) and (opening or via or hole ) and etch\$3) and ("xenon difluoride" or "XeF.sub.2")	USPAT; EPO; JPO; IBM_TDB	2002/07/15 15:38